

<b>Notice of References Cited</b>	Application/Control No. 10/769,235	Applicant(s)/Patent Under Reexamination HATCHELL, SHEILA A.	
	Examiner David T. Fidei	Art Unit 3728	Page 1 of 1

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*	B	US-5,915,549 A	06-1999	Palmer et al.	206/308.1
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	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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